

Physical Characterization

We offer a broad range of techniques such as particle counts, EDS, Raman, PL, FTIR, Hall measurements, spectrophotometer (UV-VIS-NIR), haze, contact angle, stylus profilometry, optical profilometry, and nano-indentation.

METROLOGY	FORM FACTOR	MEASUREMENT TYPE	DATA PROVIDED	PRICE / SAMPLE, \$
XRR	Coupon, 200mm, 300mm	1 pt measurement	Thickness Density	\$353.50
		3 pt measurement		\$558.50
		5 pt measurement		\$763.50
		10 pt measurement		\$1,378.50
		13 pt measurement		\$1,686.00
XRD		1 pt measurement*	Spectra with peak identification	\$558.50
XPS	Small wafer piece, we can cleave here	Survey scan only	Element identification composition (based on available sensitivity factors)	\$820.00
		Survey scan Detailed scans of up to three elements	Element identification composition (based on available sensitivity factors) Detailed scan spectra (no peak fitting)	\$1,025.00
		Survey scan Detailed scans of up to three elements Peak fitting		\$1,640.00
		Survey scan Detailed scans of up to six elements		\$1,230.00
		Survey scan Detailed scans of up to six elements Peak fitting		\$2,460.00
XRF	Coupon, 200mm, 300mm	24 pt measurement (up to 5 elements, provided we have the channels)		Raw XRF counts
AFM	Coupon, 200mm	1 pt measurement	RMS roughness Image	\$558.50
SEM	Coupon		Image	\$820.00
Ellipsometry	Coupon, 200mm, 300mm	Up to 49 pt measurement (for films with models previously built)	Thickness, n, k	\$558.50
		Up to 49 pt measurement (Build model with standards)		\$1,527.00